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V.	4	50. (Amended)	A method of simulating Euclidean wiring in an
'B\	2	integrated circuit ayout, said method	comprising:
V	3	determining a preferred wiring	g angle for a metal layer of said integrated circuit
	4	layout; \	•
	5	determining a ratio of first inte	erconnect line length along a first direction to a
	6	second interconnect line le	ength along a second direction that is approximately
A2	7	45 degrees from said first	direction to create a simulated interconnect line
	8	along said preferred wiring	g angle; and
	9	routing said metal layer using	said preferred wiring angle by creating interconnect
O	10	wires made up of wire seg	ments of said first interconnect line length along
ā	11	said first direction and win	re segments of said second interconnect line length
	12	along said second directio	n.
	1	60. (Amended)	The method of claim 59 wherein said first direction
		· · · · · · · · · · · · · · · · · · ·	
triam trans trans trans trans	2	is notizontal and said second direction	n is substantially 45 degrees from said horizontal.
	1	61. (Amended)	The method of according to claim 59 further
	2	comprising:	
٠	3	routing a first interconnect lin	e along said preferred wiring angle by connecting
	4	alternating pairs of said fir	est interconnect line length along said first direction
	5	and said second interconne	ect line length along said second direction.

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	1	62. (Amended) A method of simulating Euclidean wiring, said
	2	method comprising:
	3	determining a preferred wiring angle for a metal layer;
12	4	determining a ratio of a first interconnect line length along a first direction to a
	5	second interconnect line length along a second direction that is substantially
	6	orthogonal to said first direction to create a simulated interconnect line along
	7	said preferred wiring angle; and
	8	routing said metal layer using said preferred wiring angle.
	1	64. (Amended) The method of according to claim 62 further
\ \ MI	2	comprising:
	3	routing a first interconnect line along said preferred wiring angle by connecting
	4	alternating pairs of an interconnect line length along said first direction and an
	5	a substantially orthogonal interconnect line length along said second direction.
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1	1	65. (Amended) An integrated circuit layout, said integrated circuit
	2	layout comprising:
	3	a plurality of circuit modules;
	4	a first interconnect line layer, said first interconnect line layer having a preferred
	5	horizontal direction of interconnect lines;
	6	a second interconnect line layer, said second interconnect line layer with having a
	7	preferred vertical direction of interconnect lines; and

	ð	a third interconnect line layer, said third interconnect line layer naving a first
	9	arbitrary diagonal preferred direction;
	10	wherein interconnect lines on said third interconnect line layer comprise a plurality of
	11	alternating interconnect ine subsegments wherein a first subsegment is horizontal and a
	12	second subsegment is approximately 45 degrees diagonal to said horizontal.
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	1	66. (Amended) The integrated circuit layout as claimed in claim 65,
	2	said integrated circuit layout further comprising:
	3	a fourth interconnect line layer, said fourth interconnect line layer having a second
	4	diagonal preferred direction, said second diagonal preferred direction
N.	5	substantially orthogonal to aid first diagonal preferred direction wherein
	6	interconnect lines on said fourth interconnect line layer comprise a plurality of
4	7	alternating interconnect line subsegments.
	1 .	68. (Amended) The integrated circuit layout as claimed in claim 66,
:	2	said integrated circuit layout further comprising:
4	3	a fifth interconnect line layer, said fifth interconnect line layer having a second
	4	diagonal preferred direction, said second diagonal preferred direction
	5	substantially orthogonal to said first diagonal preferred direction wherein
	6	interconnect lines on said fifth interconnect line layer comprise a plurality of
	7	alternating interconnect line subsegments.

	1	69 (Amended) A method of laying out an integrated circuit, said
	2	method comprising
	3	placing a plurality of circuit modules;
	4	routing a first interconnect line layer, said first interconnect line layer having a
	5	preferred horizontal direction of interconnect lines;
	6	routing a second interconnect line layer, said second interconnect line layer with
AL	r ₇	having a preferred vertical direction of interconnect lines; and
	8	routing a third interconnect line layer, said third interconnect line layer having a
	9	first preferred diagonal direction;
Ö	10	wherein interconnect lines on said third interconnect line layer comprise a plurality of
ā	11	alternating interconnect line subsegments wherein a first subsegment is horizontal and a
	12	second subsegment is approximately 45 degrees diagonal to said horizontal.
	1	70. (Amended) The method of laying out said integrated circuit
	2	layout as claimed in claim 69, said method further comprising:
	3	routing a fourth interconnect line layer, said fourth interconnect line layer having a
	4	second diagonal preferred direction, said second diagonal preferred direction
	5	substantially orthogonal to said first diagonal preferred direction wherein
	6	interconnect lines on said fourth interconnect line layer comprise a plurality of

alternating interconnect line subsegments.

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T	72. (Added) A method of faying out an integrated circuit, said method
2	comprising:
3	placing a plurality of circuit modules;
4	routing a first interconnect line layer, said first interconnect line layer having a
5	preferred horizontal direction of interconnect lines;
6	routing a second interconnect line layer, said second interconnect line layer with
7	having a preferred vertical direction of interconnect lines; and
8	routing a third interconnect line layer, said third interconnect line layer having a
9	first preferred diagonal direction;
10	wherein interconnect lines on said third interconnect line layer comprise a plurality of
11	alternating interconnect line subsegments wherein a first subsegment is horizontal and a
12	second subsegment is substantially orthogonal to said horizontal.
1	73. (Added) The method of laying out said integrated circuit layout as
2	claimed in claim 72, said method further comprising:
3	routing a fourth interconnect line layer, said fourth interconnect line layer having a
4	second diagonal preferred direction, said second diagonal preferred direction
5	substantially orthogonal to said first diagonal preferred direction wherein
6	interconnect lines on said fourth interconnect line layer comprise a plurality of
7	alternating interconnect line subsegments

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to said preferred horizontal direction.

74. (Added) The method of laying out said integrated circuit layout as
claimed in claim 72, said method wherein said first diagonal preferred direction is
approximately forty-five degrees relative to said preferred horizontal direction and said
second diagonal preferred direction is approximately negative forty-five degrees relative

The Amended Claims

The following pages provide the amended claims with the amendments marked with deleted material in [brackets] and new material underlined.

	. 1	39. (Amended) A method of simulating Euclidean wiring <u>in an</u>
	2	integrated circuit layout, said method comprising:
	3	determining a preferred wiring angle for a metal layer of said integrated circuit
	4	layout;
	5	determining a ratio of [an] first interconnect line length along a first direction to a
	6	second [diagonal] interconnect line length along a second direction that is
	7	approximately 45 degrees from said first direction to create a simulated
	8	interconnect line along said preferred wiring angle; and
	9	routing said metal layer using said preferred wiring angle by creating interconnect
	10	wires made up of wire segments of said first interconnect line length along
	11	said first direction and wire segments of said second interconnect line length
	12	along said second direction.

- 60. (Amended) The method of claim 59 wherein said first direction 1
- is horizontal and said second direction is substantially 45 degrees from said horizontal. 2

	1	61. (Amended) The method of according to claim 59 further
	2	comprising:
	3	routing a first interconnect line along said preferred wiring angle by connecting
٠	4	alternating pairs of said first [an] interconnect line length along said first
	5	direction and [a] said second [diagonal] interconnect line length along said
	6	second direction.
	1	62. (Amended) A method of simulating Euclidean wiring, said
]	2	method comprising:
]	3	determining a preferred wiring angle for a metal layer;
1	4	determining a ratio of a first interconnect line length along a first direction to a
	5	second interconnect line length along a second direction that is [approximately
•	6	90 degrees from] substantially orthogonal to said first direction to create a
	7	simulated interconnect line along said preferred wiring angle; and
	8	routing said metal layer using said preferred wiring angle.
	1	64. (Amended) The method of according to claim 62 further
	2	comprising:
	3	routing a first interconnect line along said preferred wiring angle by connecting
	4	alternating pairs of an interconnect line length along said first direction and an
	5	a substantially orthogonal [orthognal] interconnect line length along said
	6	second direction.

1	65. (Amended) An integrated circuit layout, said integrated circuit
2	layout comprising:
3	a plurality of circuit modules;
4	a first interconnect line layer, said first interconnect line layer having a preferred
5	horizontal direction of interconnect lines;
6	a second interconnect line layer, said second interconnect line layer with having a
7	preferred vertical direction of interconnect lines; and
8	a third interconnect line layer, said third interconnect line layer having a first
9	arbitrary diagonal preferred direction;
10	wherein interconnect lines on said third interconnect line layer comprise a plurality of
11	alternating interconnect line subsegments wherein a first subsegment is horizontal and a
12	second subsegment is approximately 45 degrees diagonal to said horizontal [first
13	subsegment].
1	66. (Amended) The integrated circuit layout as claimed in claim 65,
2	said integrated circuit layout further comprising:
3	a fourth interconnect line layer, said fourth interconnect line layer having a second
4	diagonal preferred direction, said second diagonal preferred direction
5	substantially orthogonal to said first diagonal preferred direction wherein
6	interconnect lines on said fourth interconnect line layer comprise a plurality of
7	alternating interconnect line subsegments.

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1	68. (Amended) The integrated circuit layout as claimed in claim 66
2	said integrated circuit layout further comprising:
3	a fifth interconnect line layer, said fifth interconnect line layer having a second
4	diagonal preferred direction, said second diagonal preferred direction
5	substantially orthogonal to said first diagonal preferred direction wherein
6	interconnect lines on said fifth interconnect line layer comprise a plurality of
7	alternating interconnect line subsegments.

1	69. (Amended)	A method of laying out an integrated circuit, said
2	method comprising:	
3	placing a plurality of circuit modules;	
4	routing a first interconnect	line layer, said first interconnect line layer having a
5	preferred horizontal dire	ection of interconnect lines;
6	routing a second interconne	ect line layer, said second interconnect line layer with
7	having a preferred verti	cal direction of interconnect lines; and
8	routing a third interconnect	line layer, said third interconnect line layer having a
9	first preferred diagonal	direction;
10	wherein interconnect lines on said	third interconnect line layer comprise a plurality of
11	alternating interconnect line subseg	gments wherein a first subsegment is horizontal and a
12	second subsegment is approximate	ly 45 degrees diagonal to said horizontal [first
13	subseament]	

1	70. (Amended) The method of laying out said integrated circuit	
2	layout as claimed in claim 69, said method further comprising:	
3	routing a fourth interconnect line layer, said fourth interconnect line layer having a	
4	second diagonal preferred direction, said second diagonal preferred direction	
5	substantially orthogonal to said first diagonal preferred direction wherein	
6	interconnect lines on said fourth interconnect line layer comprise a plurality of	
7	alternating interconnect line subsegments.	